

## Michael Bruce receives the 2022 EDFAS Lifetime Achievement Award



The **EDFAS Lifetime Achievement Award** recognizes those who have given their time, knowledge, and abilities toward the advancement of the electronic device failure analysis industry. The 2022 awardee is **Dr. Michael Bruce**, consultant, Austin, TX. His citation reads: “for his lifetime contributions to the advancement of backside failure analysis techniques and the development and adoption of Soft Defect Localization, which has become a mainstay tool across the Semiconductor Industry.”

Dr. Bruce has over 27 years of experience in the semiconductor industry applying optical based fault isolation techniques. He has a BS and PhD in Physics from the University of Texas at Austin and conducted post doctoral research in chemical physics at Indiana University. He worked 14 years at Advanced Micro Devices, Inc. in reliability and failure analysis. At AMD, he has developed many optical based tools and techniques for debug of microprocessors including Soft Defect Localization (SDL) for isolating speed paths in IC's, single element Time Resolved Emission (TRE), and Resistive Interconnect Localization (RIL). He currently provides technical consultation to SEMICAPS Ptd Ltd. and many other organizations. Mike holds 76 patents and has published numerous papers in referred journals and conferences, including a best paper and outstanding paper at ISTFA for RIL and SDL, respectively. He is current past editor of the *Electronic Device Failure Analysis* magazine and has served on numerous technical committees at Sematech, ISTFA, IPFA, and IRPS.